EVENT BASED TEST SYSTEM HAVING IMPROVED

SEMICONDUCTOR CHARACTERIZATION MAP

Abstract of the Disclosure

An event based test system having [an improved] *GL*
5   characterization tool for semiconductor device testing. The
characterization map provides multi-dimensional views of
device performance for debug of the design, and
identification of performance weaknesses. The
characterization map tool exploits the capabilities of the
10   event based test system. The multi-dimensional views
include a checkerboard map such as displaying pins versus
time, a shmoo plot showing pass-fail boundary points
relative to predetermined parameters, or a margin map
showing a pass/fail range for pins corresponding with timing
15   changes in one or more events.

20

SPC-AD37.002
110901

25